

IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Lawrence C. LEI et al.

Serial No. 10/685,210

Filed: October 14, 2003

For: METHOD AND APPARATUS FOR MEASURING OBJECT THICKNESS



:

:

:

:

:

:

Group Art Unit: 2858

Examiner: Jay M. Patidar

Fee
only

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom. Copies of any cited U.S. Patents and U.S. Patent Publications are not being submitted in accordance with 37 CFR 1.98(a)(2)(i).

In accordance with 37 C.F.R. § 1.97(g) and (h), the filing of this IDS should not be construed as a representation that a search had been made or that information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56 (b), or that any cited document listed or attached is (or constitutes) prior art. Unless otherwise indicated, the date of publication indicated for an item is taken from the face of the item, and Applicant reserves the right to prove that the date of publication is in fact different.

The reference listed on Sheet 1 of the attached PTO-1449 Form was cited in a PCT application corresponding to the above-referenced application not more than three months before

04/26/2005 RJTJMS01 00000009 030219 10685210
72 FC:1606 180.00 DA